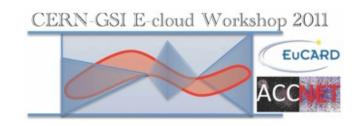




# Review on Electron Cloud simulation tools @ CERN

G. Rumolo in CERN-GSI Workshop on Electron Cloud Monday 07.03.2011

Acknowledgments: G. Arduini, G. Bellodi, E. Benedetto, J. Crittenden, O. Dominguez, W. Fischer, G. Franchetti, U. Iriso, K. Li, K. Ohmi, E. Shaposhnikova, F. Zimmermann

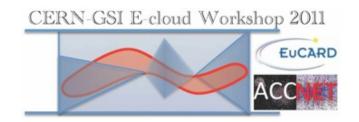






#### Outline

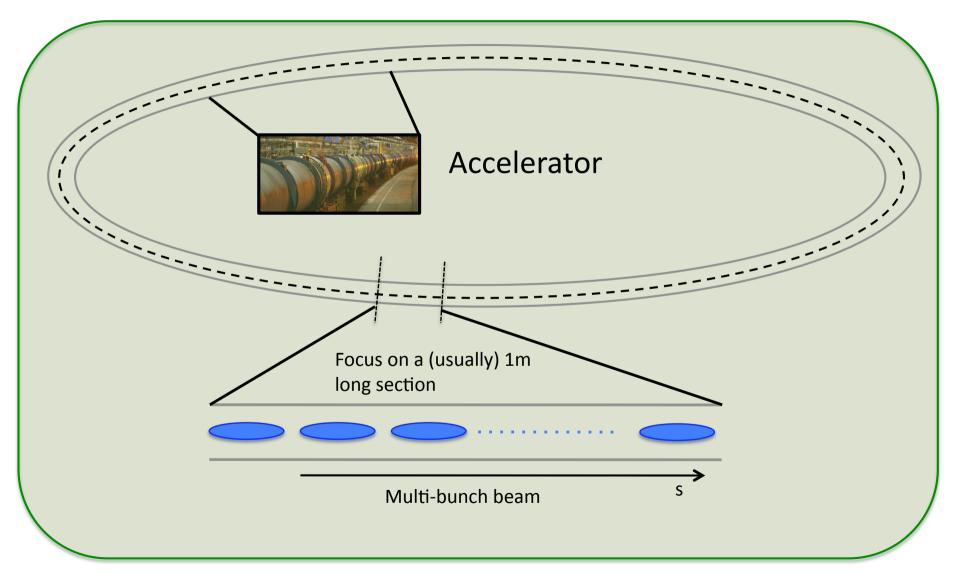
- General considerations on electron cloud simulations:
  - Beam induced build up
  - Effects on the beam
- CERN tools
  - ECLOUD
    - → Model and numerical parameters
    - → Sensitivity to physical parameters
  - HEADTAIL







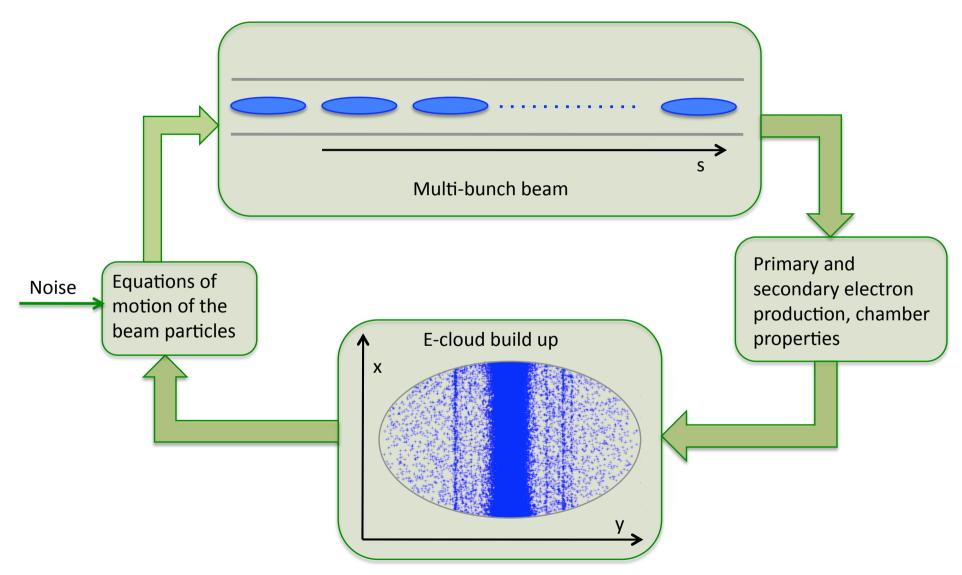
#### The electron cloud physics problem







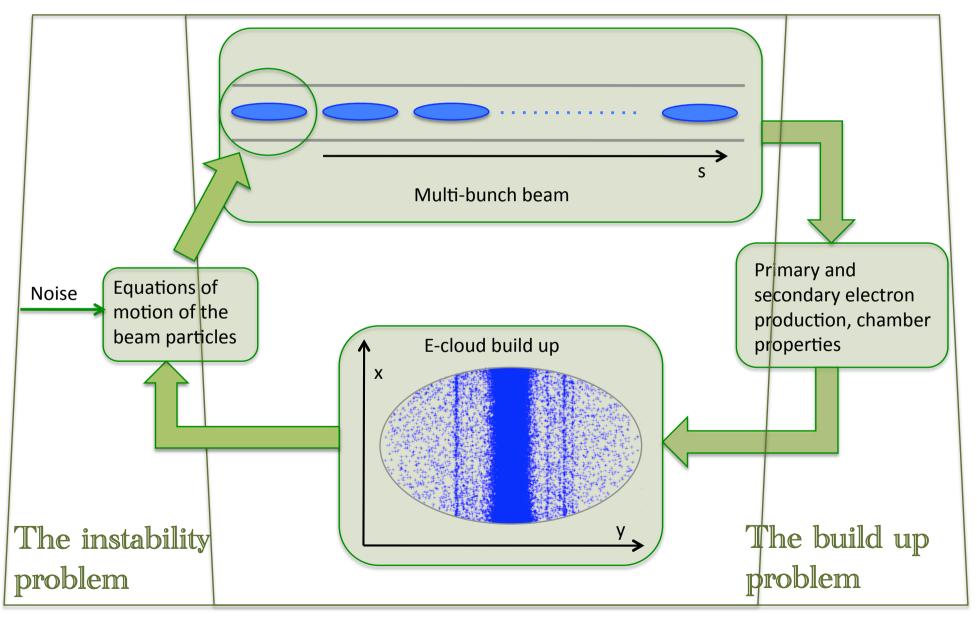
## Flow chart of the e-cloud physics problem







#### Splitting the problem...



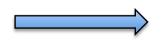




#### In summary

- Coupled bunch electron cloud instability naturally needs a selfconsistent solution of the electron cloud problem
  - Too broad range of time scales to cover
- So we choose to simulate the two branches separately:
  - Electron cloud build up
    - ✓ Multi-bunch
    - ✓ Usually single passage, single turn
  - Electron cloud instability
    - ✓ Single bunch
    - ✓ Multi-turn, or even multi-kick multi-turn

**Build up simulation** 



**Instability simulation** 

Information on how many electrons interact with a bunch:

- central density
- detailed distribution





## Simulation of e-cloud build up Existing codes

- Electron cloud build up codes:
  - ECLOUD (CERN, Zimmermann, Bellodi, Brüning, Crittenden, Rumolo, Schulte, Xiang)
  - POSINST (LBNL, Furman, Pivi)
  - CLOUDLAND (BNL-SLAC, Wang)
  - CSEC (BNL, Blaskiewicz)
  - PEI (KEK, Ohmi)
  - FAKTOR2 (CERN, Bruns)





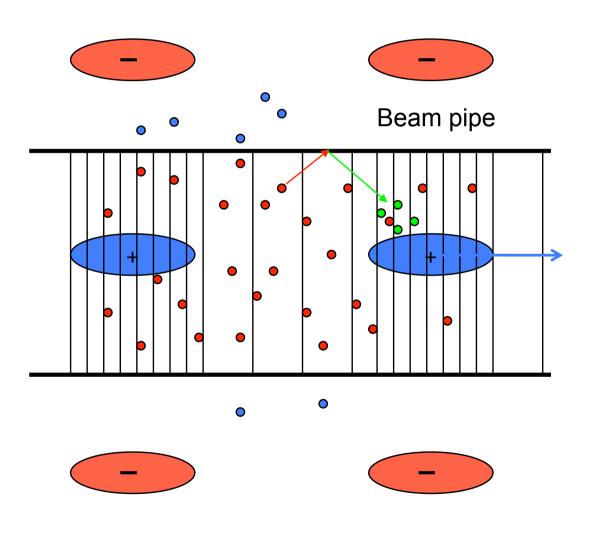
## Main ingredients of ECLOUD

- Multi-bunch passage, dipole/field-free/ solenoid sections, clearing voltage
- 3D electron kinematics
- Transverse beam-electron forces
- Transverse electron space charge effects
- Circular/elliptical/rectangular chamber
- Perfectly conducting walls









- focus on a beam line section (1m for ex.)
- slice bunch and interbunch gaps
- represent e- by macroparticles: create and accelerate e- in beam and image fields
- if the macroelectron hits the wall create secondaries by changing its charge and/or splitting into more macroelectrons





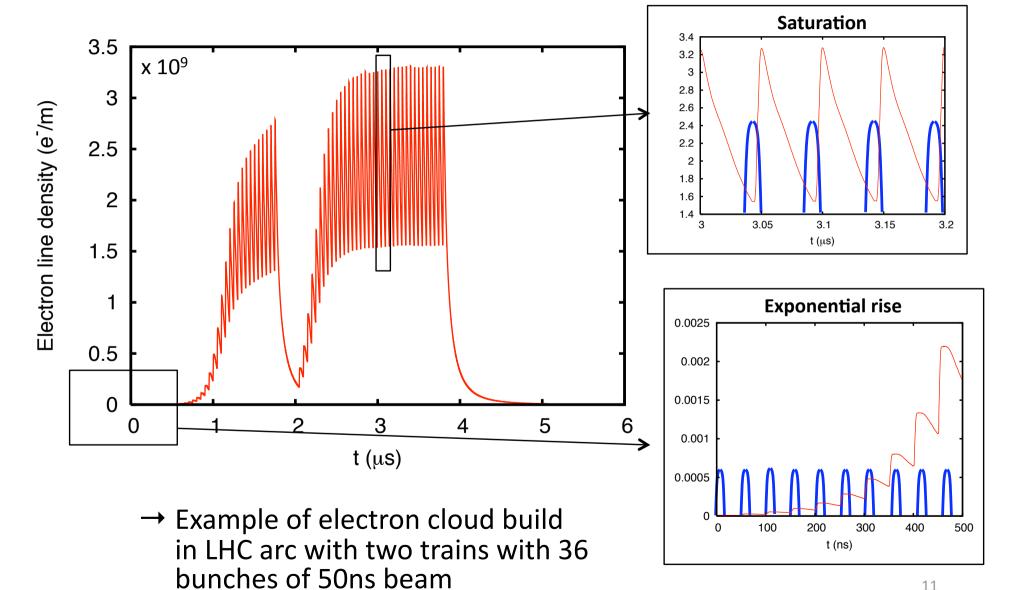
### Dependence on numerical parameters

- → Electron cloud build up simulations are sensitive to a significant number of numerical parameters
  - Time steps:
    - ✓ During the bunch passage
    - ✓ During the inter-bunch gap
  - Number of macro-electrons launched per bunch
  - Maximum number of macro-electrons allowed in the simulation
    - ✓ Macro-electrons are not just produced all the time through the primary and secondary generation mechanisms
    - ✓ A 'clean' subroutine always reduces the number of macro-electrons back to the maximum allowed, when exceeded, and the "cleaned" charge is redistributed
  - Limit charge for macro-electron splitting and maximum number of macro-electrons into which a macro-electron that has 'gained' too much charge can be split
  - Number of mesh points for space charge calculation
  - Multi-seed simulations for statistics
- → CPU times of typical electron cloud build up simulations range from few hours to several days, depending on the choice of the parameters above (determined by the problem)





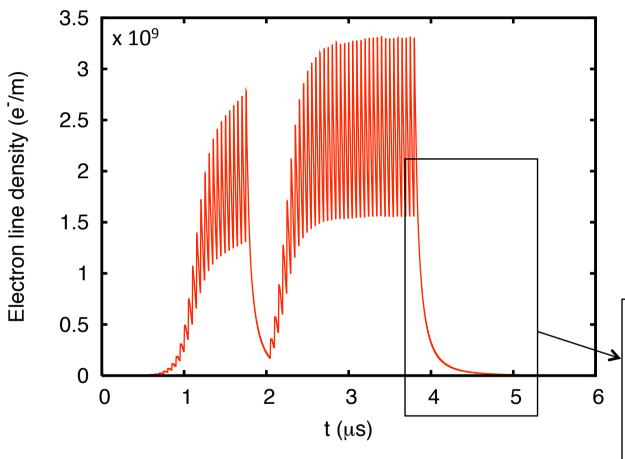
#### **ECLOUD** sample result



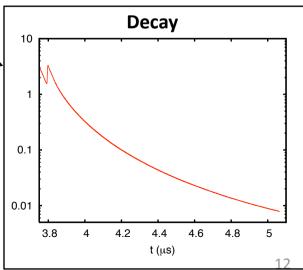




#### **ECLOUD** sample result



→ Example of electron cloud build in LHC arc with two trains with 36 bunches of 50ns beam







#### Dependence on physical parameters

- → Electron cloud build up depends on a significant number of parameters in a non-monotonic and non-trivial way
  - Primary mechanism of electron generation
    - ✓ Gas ionization or beam loss (hadrons)
    - ✓ Photoemission (positrons, LHC)
  - Surface properties:
    - ✓ Maximum SEY ( $\delta_{max}$ ) and energy at which it occurs ( $E_{max}$ )
    - ✓ Probability of reflection at zero energy  $(R_0)$
    - ✓ Existence and model of re-diffused electrons
  - Bunch spacing and bunch length
  - Beam pipe radius and shape
  - Magnetic field (field-free, dipole, quadrupole)
  - Beam transverse sizes
  - Beam current (number of particles per bunch)





#### Dependence on physical parameters

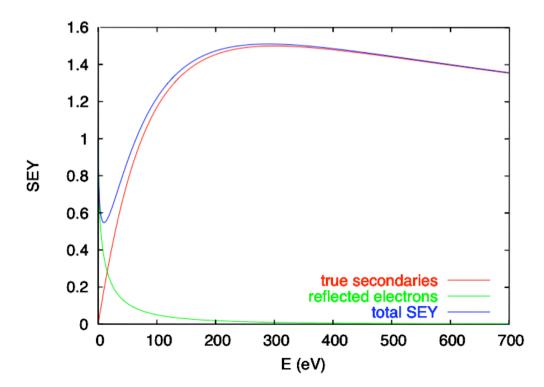
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#### Surface model

- When electrons hit the pipe wall, they do not just disappear.....
  - High energy electrons easily survive and actually multiply through secondary electron emission
  - Low energy electrons tend to survive long because they are likely to be elastically reflected.
- Secondary electron emission is governed by the curve below (as coded in ECLOUD)



$$\delta_{\text{true}} = \delta_{\text{max}} \frac{sx}{s - 1 + x^s} \qquad x = \frac{E}{E_{\text{max}}}$$

$$\delta_{\text{elas}} = \frac{\left(\sqrt{E} - \sqrt{E + E_0}\right)^2}{\left(\sqrt{E} + \sqrt{E + E_0}\right)^2}$$

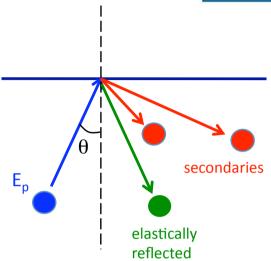
$$\delta_{\text{tot}}(E) = \delta_{\text{true}}(E) + R_0 \cdot \delta_{\text{elas}}(E)$$





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First three parameters on which simulation results depend

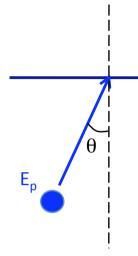
$$(R_0, E_{\max}, \delta_{\max})$$

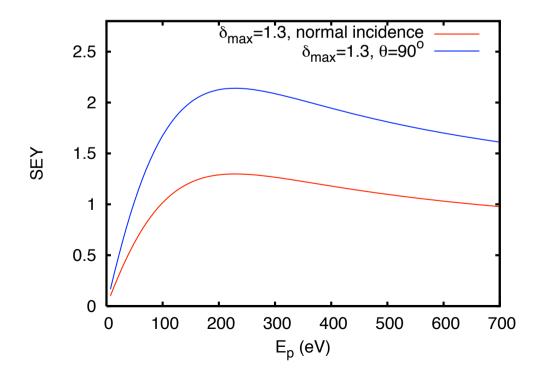




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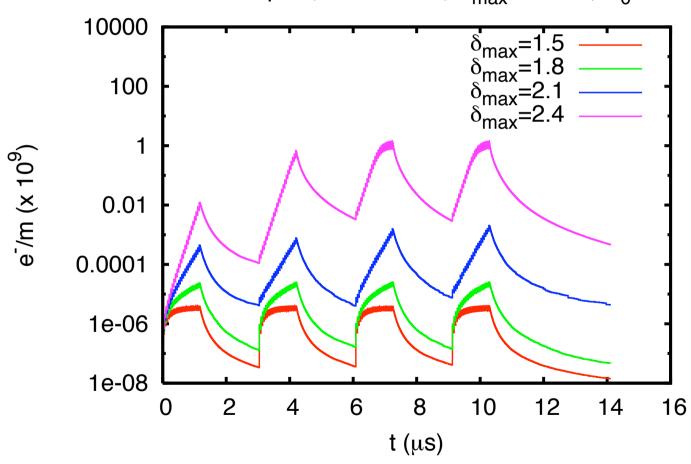
$$\delta_{\max}^*(\theta) = \delta_{\max} \exp\left[\frac{1}{2} (1 - \cos \theta)\right]$$
$$E_{\max}^*(\theta) = E_{\max} \cdot [1 + 0.7 (1 - \cos \theta)]$$





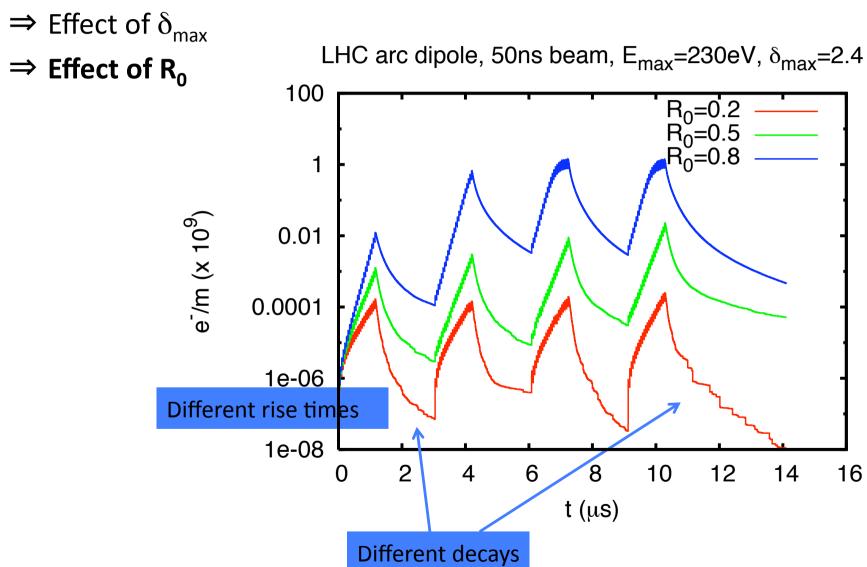
 $\Rightarrow$  Effect of  $\delta_{\text{max}}$ 

LHC arc dipole, 50ns beam,  $E_{max}$ =230eV,  $R_0$ =0.8



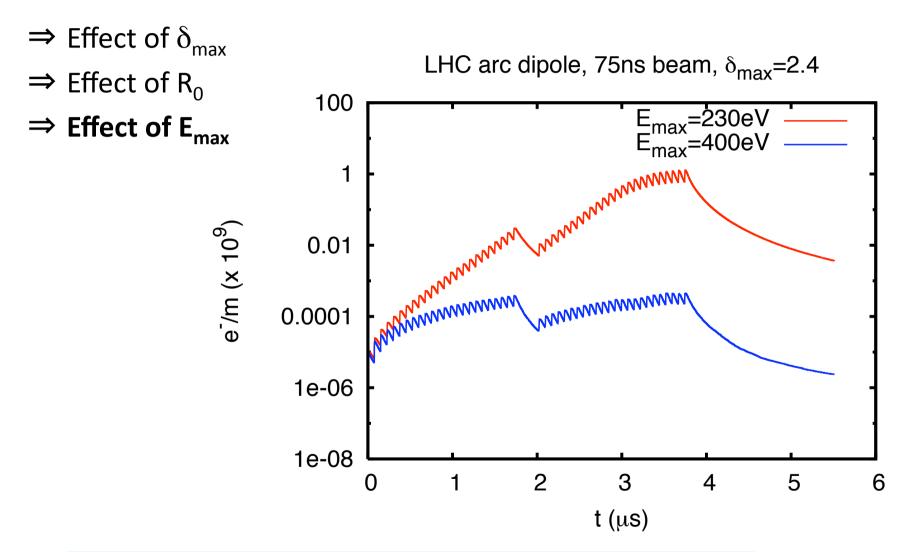
















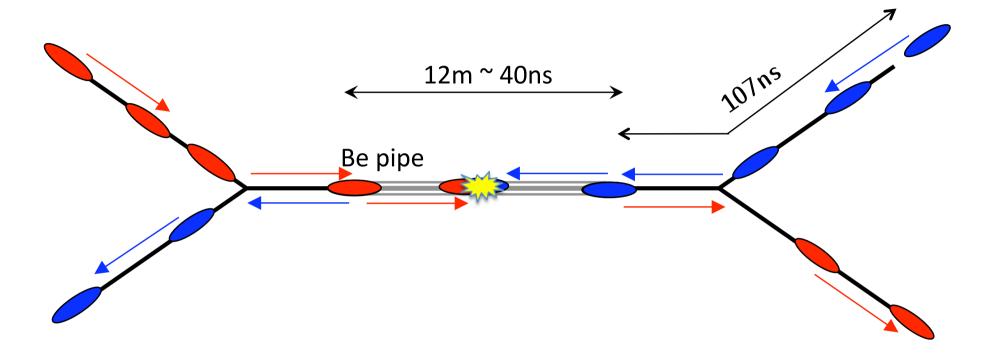
#### Dependence on physical parameters

- → Electron cloud build up depends on a significant number of parameters in a non-monotonic and non-trivial way
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  - Magnetic field (field-free, dipole, quadrupole)
  - Beam transverse sizes
  - Beam current (number of particles per bunch)





## Dependence on bunch spacing and length

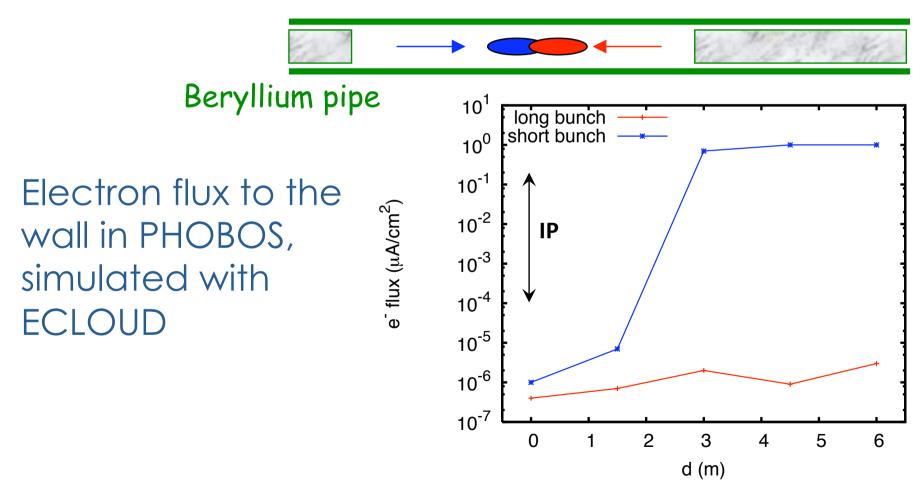


- → One of the former experimental regions of RHIC (PHOBOS)
- → Electron cloud is likely to build up, especially because in the experimental region there is a **beryllium pipe** (very high SEY), and the **effective bunch spacing is reduced**
- → **Observation**: when bunches are compressed to half length, a severe pressure rise occurs in the PHOBOS region, which later "switches off" at some stage during the store.













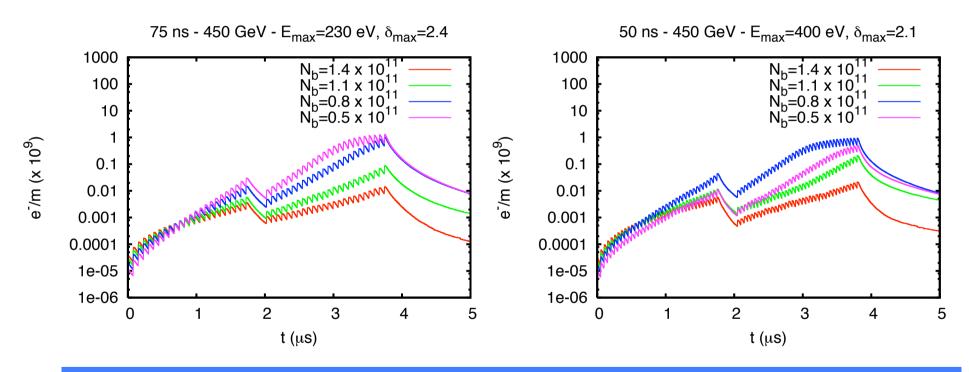
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 $\Rightarrow$  Effect of N<sub>b</sub>



75ns  $\rightarrow$  electron cloud decreasing function o 50ns  $\rightarrow$  electron cloud is maximum for 8 x 10<sup>10</sup> ppb

Non-monotonic & counterintuitive – to be experimentally verified!!





## Simulation of e-cloud instability Existing codes

- Electron cloud instability codes:
  - PEHTS (KEK, Ohmi)
  - **HEADTAIL** (*CERN*, Rumolo, Zimmermann, et al.)
  - QUICKPIC (USC-GSI, Katsouleas, Ghalam, Rumolo, Benedetto, Beng)
  - WARP-POSINST (LBNL, Vay, Furman)
  - CMAD (SLAC, Pivi)

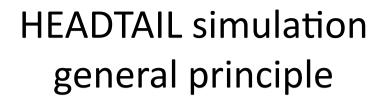




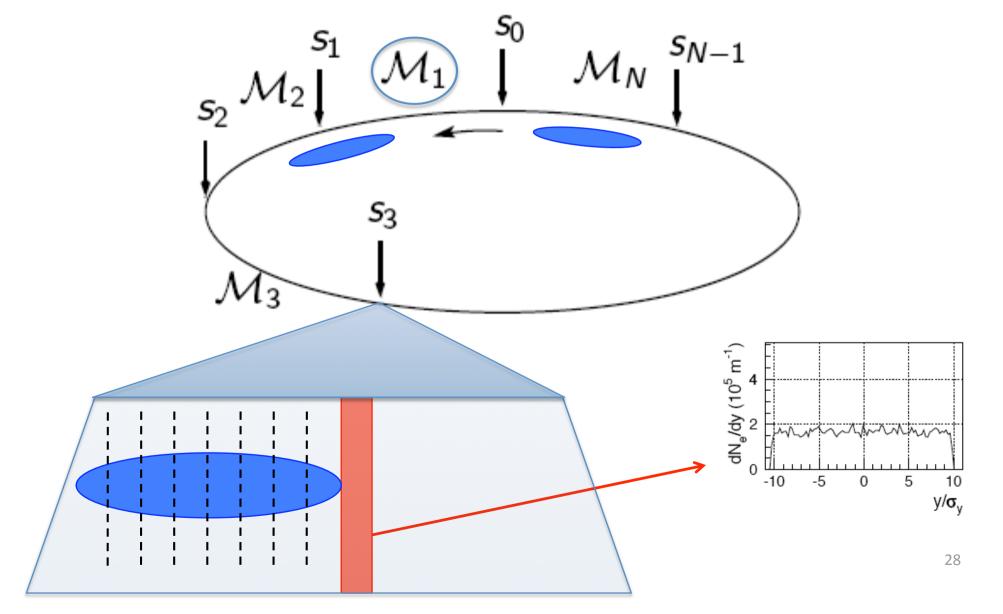
## Main ingredients of HEADTAIL

- Single-bunch effect
- Multi-turn and multi-kick
- Dipole/field-free/solenoid sections
  - Can receive the electron distribution from ECLOUD
- 6D bunch description
  - Several options for the type of longitudinal motion
- Transverse mutual beam-electron forces
- Chromaticity, amplitude detuning

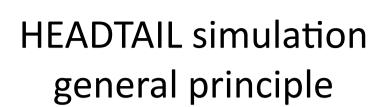




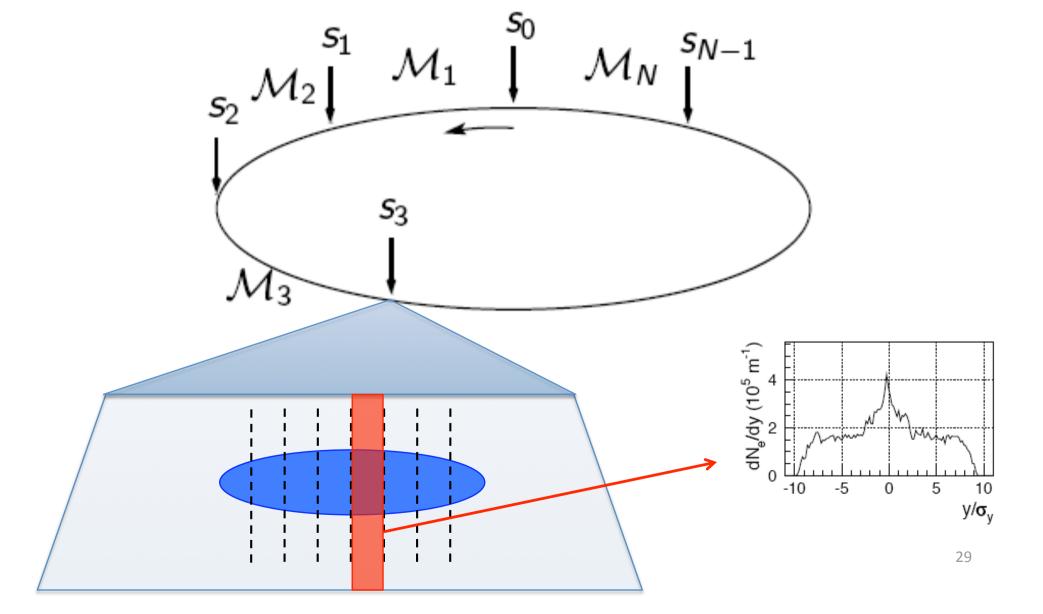




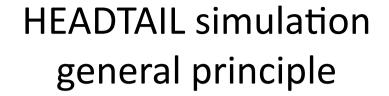




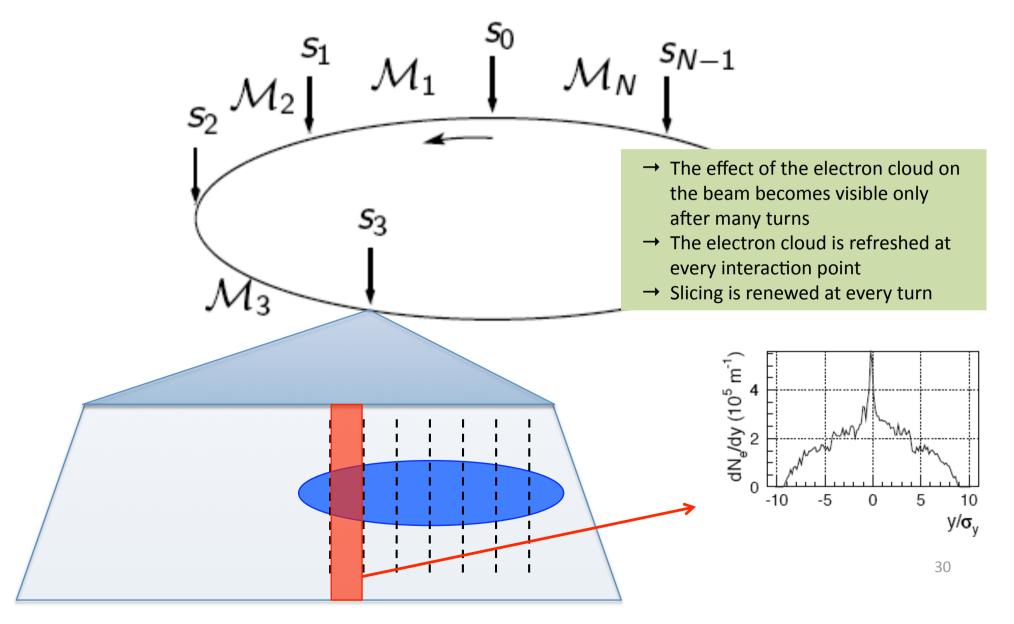
















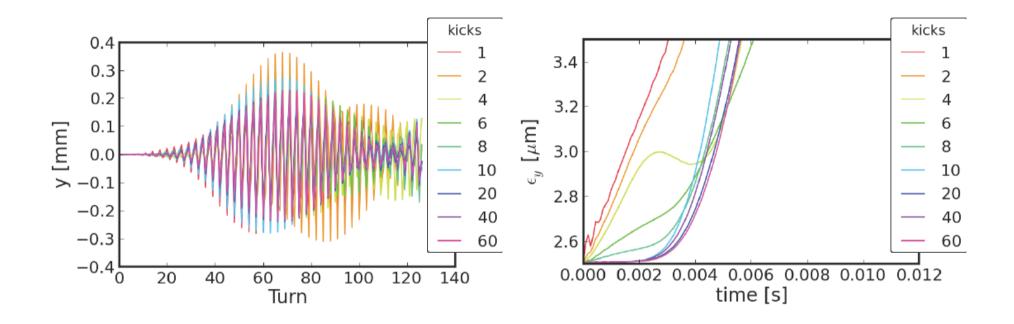
### Dependence on numerical parameters

- → Electron cloud instability simulations are sensitive to a significant number of **numerical parameters** 
  - Time steps:
    - ✓ Number of slices chosen to represent the bunch
    - ✓ Number of electron kicks per turn
  - Number of macro-particles
    - ✓ How many macro-electrons?
    - ✓ How many bunch macro-particles?
    - ✓ How many bunch macro-particles per bunch slice?
  - Extension of the electron cloud transverse area, which is the grid to be meshed (usually a certain number of the beam transverse sigmas)
  - Number of grid points for the Poisson mesh
  - Type of Poisson solver (with or w/o boundary conditions on a rectangle)
- → CPU times for electron cloud instability simulations span from few hours to several days according to the settings





#### Importance of numerical parameters



- → Number of kicks per turn can be used
  - 1. for 'lumping' in a certain number of locations the action of a continuous electron cloud, or
  - 2. kicks represent real localized electron clouds in the accelerator
- → In case 1., if number of kicks per turn is too low, coherent motion may be turned into incoherent





## Dependence on physical parameters

- → In principle both coherent instability and incoherent emittance growth could be predicted by these simulations
- → Evolution of a beam interacting with an electron cloud depends on a significant number of parameters in a non-trivial way
  - Bunch length (longitudinal emittance)
  - Beam transverse sizes (emittances and beta functions at the electron cloud location)
  - Beam energy
  - Beam current (number of particles per bunch)
  - Chromaticity
  - Magnetic field (field-free, dipole, quadrupole)
  - Electron cloud density and distribution (in reality determined by many of the above parameters, but can be set independently in simulations)





## Dependence on physical parameters

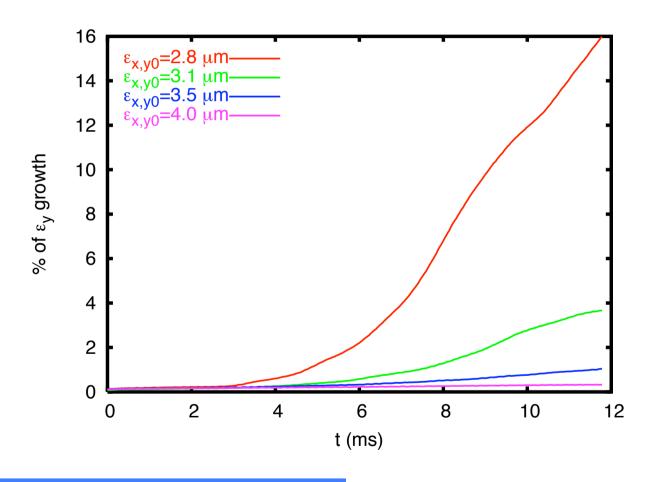
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#### Effects on instability

 $\Rightarrow$  Effect of  $\epsilon_{x,y}$ 



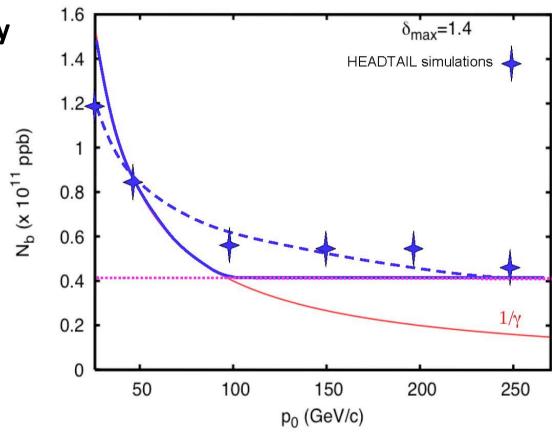
→ The pinch around small emittances is enhanced and makes the bunch more unstable





#### Effects on instability

- $\Rightarrow$  Effect of  $\varepsilon_{x,y}$
- **⇒** Effect of beam energy



 → Instability threshold decreases with energy (keeping emittances + bunch length constant)





#### Conclusions & Outlook

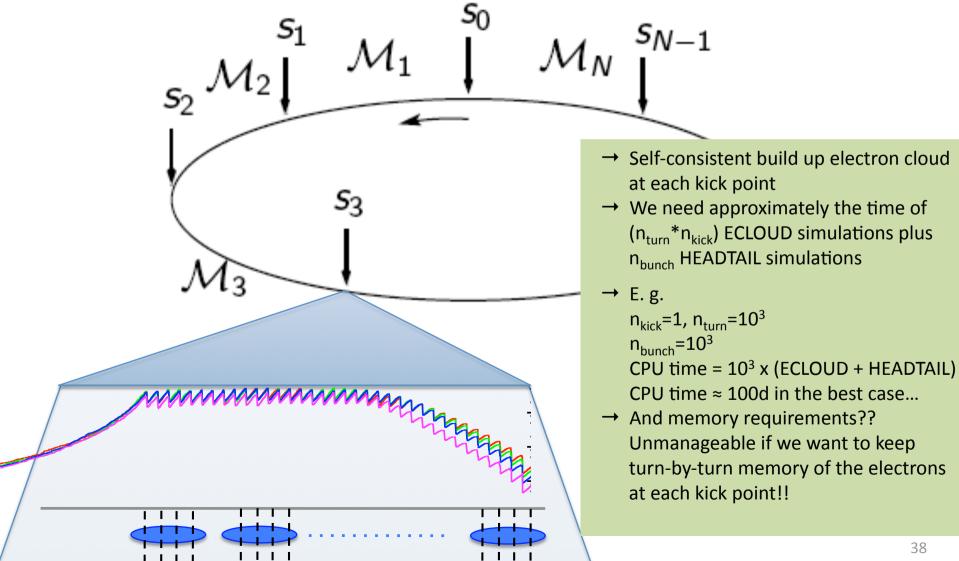
- Electron cloud simulations are split into:
  - Build up simulations
  - Beam dynamics simulations
- CERN tools
  - ECLOUD & HEADTAIL
    - → Sensitive to several model and numerical parameters
    - → Unveiled non-trivial dependence on physical parameters
- Outlook: unify build up and instability simulations in one 3D self-consistent model ??





#### THE DREAM OF A 3D SELF-CONSISTENT **DESCRIPTION...**



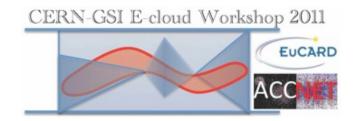




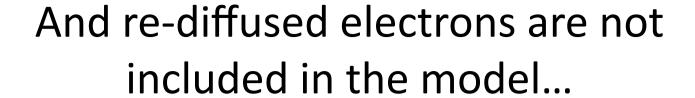


#### Conclusions & Outlook

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  - Build up simulations
  - Beam dynamics simulations
- CERN tools
  - ECLOUD & HEADTAIL
    - → Sensitive to several model and numerical parameters
    - → Unveiled non-trivial dependence on physical parameters
- Outlook: prove further & improve the reliability of our codes, develop & include more functionalities, grab the physics in our models

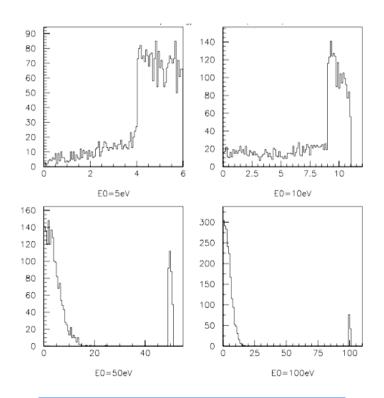




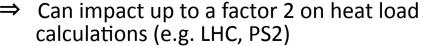




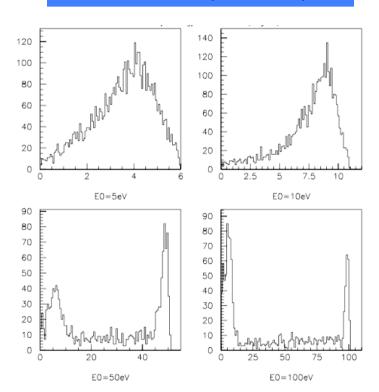
⇒ In the present ECLOUD model, electrons are either reflected or cause secondary emission



⇒ Re-diffused electrons enhance the build up



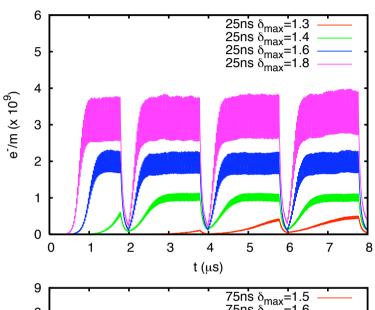
#### With re-diffused (G. Bellodi)

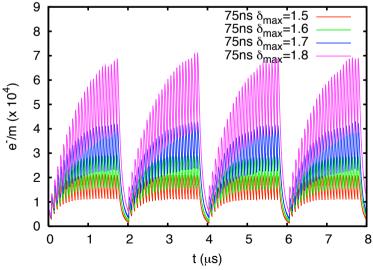


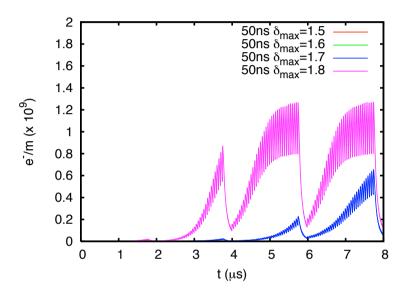












- → Example of electron cloud build in an SPS MKD kicker for different kinds of beam
  - 25ns bunch spacing has electron cloud even for  $\delta_{\text{max}} \text{=} 1.3$
  - 50ns bunch spacing builds electron cloud for  $\delta_{\text{max}}{>}1.6$
  - 75ns does not have electron cloud up to  $\delta_{max}$ =1.8